1<sup>st</sup> CARAT Workshop © GSI Darmstadt 2009 13–15 December 2009

# Heteroepitaxial diamond on Ir/YSZ/Si(001): general developments and specific aspects for detector applications

Matthias Schreck

S. Gsell, M. Fischer, S. Dunst, Ch. Stehl, B. Stritzker

Universität Augsburg, Institut für Physik, D-86135 Augsburg (GERMANY)



# OUTLINE

- Competing concepts for growth of diamond with low defect density
- Heteroepitaxy of diamond on iridium: a brief introduction
- Potential fields of applications for heteroepitaxial diamond
- Diamond films on Iridium for CARAT: specific aspects for detectors
- Outlook on future work





# TEXTURED / EPITAXIAL DIAMOND FILMS

#### nanocrystalline

microcryst. (110)-fiber text.

(100)-fiber texture



heteroepitaxial Dia/Si(001) heteroepit.: Dia/Ir/SrTiO<sub>3</sub>(001) homoepitaxy on Ib HPHT



# COARSE GRAIN POLYCRYSTALLINE FILMS





# HOMOEPITAXY



#### HRXRD rocking curves







1 mm

## SINGLE CRYSTAL DIAMOND FILMS BY HETEROEPITAXY





Schema: Transition to a single crystal film in heteroepitaxy



# A brief introduction to diamond heteroepitaxy



# HETEROEPITAXY OF DIAMOND: SEARCHING FOR THE IDEAL SUBSTRATE MATERIAL



Nucleation procedure: (a)-(c): no specific treatment (d)-(f): seeding with carbon / diamond powder (g)-(i) bias enhanced nucleation (BEN)





## HETEROEPITAXY OF DIAMOND: SEARCHING FOR THE IDEAL SUBSTRATE MATERIAL

<u>Substrate</u>	First Publication		Current state of the art
Diamond on β-SiC:	Stoner & Glass 1992		Tilt 0.6° Twist: ~2.5°
Diamond on silicon:	Jiang & Klages 1992		Tilt ~ 1° Twist ~4°
Diamond on Ir:	Ohtsuka, Suzuki,		Tilt, Twist: ~ 0.1 - 0.3°
	Sawabe, Inuzuka 1996		
Further materials: c-BN,	Cu, Ni, Co, TiC, I	Ni <sub>3</sub> Si, Ni <sub>3</sub> Ge	, Al <sub>2</sub> O <sub>3</sub>
Iridium, the very best candidate for diamond heteroepitaxy			





# BIAS ENHANCED NUCLEATION (BEN)

# Microwave plasma ball

# Substrate



# BIAS ENHANCED NUCLEATION (BEN)







## DIFFERENCES IN THE TEXTURE DEVELOPMENT: DIAMOND ON Si $\Leftrightarrow$ DIAMOND ON Ir/SrTiO<sub>3</sub>



One order of magnitude lower mosaicity

Tilt and Twist decrease with thickness !!!!



# The technological challenge: finding an appropriate multilayer system



# OXIDE SINGLE CRYSTALS vs. BUFFER LAYERS ON SILICON

### Requirements:

### a) Growth of single crystal iridium films

b) Thermal compatible with diamond



#### Dia/Ir/YSZ/Si(001)





### GROWTH OF YSZ BY PULSED LASER DEPOSITION



#### **PLD** setup

#### **KrF Excimer Laser**

25 ns / 850 mJ





#### Yttria stabilized zirconia (YSZ)

- No removal of the SiO<sub>2</sub> required
- Ablation target:  $ZrO_2$  stabilized by  $Y_2O_3$
- 5 x 10<sup>-2</sup> Pa  $O_2$  (first 600 pulses without  $O_2$ )
- Substrate temperature: 825°C
- Thickness: 20 40 nm







### Ir/YSZ/Si(001): STRUCTURE & TEXTURE





# THICK DIAMOND FILMS ON Ir/YSZ/Si(001)



45 µm thick diamond film with good adhesion to the substrate

#### 4" growth substrates



Diamond:

Tilt; Twist: 0.1 – 0.3°





### DIAMOND MOSAIC CRYSTALS FOR NEUTRON MONCHROMATORS



Mosaic crystals match neutron beam divergence and optimize integrated reflectivity at monochromacy





# NEUTRON MONOCHROMATORS



# Diamond films on Iridium for CARAT: specific aspects for detectors



### CRUCIAL PARAMETERS FOR THE DETECTOR PERFORMANCE OF SINGLE CRYSTAL DIAMOND



FIG. 2. (Color online) CCE map sensitive to hole transport, acquired at +125 V. The rectangular area has been used to extract the PHS spectra shown by the solid lines in Fig. 3.



FIG. 4. CCE cross sections of various bias voltages. (a) extracted from line A and (b) extracted from line B indicated in Fig. 2.

A. Lohstroh, P. J. Sellin, S. G. Wang, A. W. Davies, J. Parkin, R. W. Martin, P. R. Edwards: Appl. Phys. Lett. 90 (2007) 102111

Nitrogen or defects formed by nitrogen as well as dislocations strongly limit the CCE in diamond





## INTERNAL DEFECT STRUCTURE: TRANSMISSION ELECTRON MICROSCOPY (TEM)



Estimated density of dislocations for the 34  $\mu$ m film: ~ 5–10x10<sup>8</sup> cm<sup>-2</sup>

Reduction by ~ 2 orders of magnitude during textured growth



### COMPARISON WITH NATURAL DIAMOND SINGLE CRYSTALS

#### **Mosaic spread**



Typical rocking curve widths for different types of diamond crystals

Ref. S. Fujii et al. Appl. Phys. A 61 (1995) 331

### **Dislocation densities:**

Our films: 5-10 x 10<sup>8</sup> cm<sup>-2</sup>

Large natural type lla-diamonds: typical > 10<sup>8</sup>cm<sup>-2</sup> Ref.: A.R. Lang in *The Properties of Diamond* ed. by J. E. Field (Academic, London 1979)



### COMPARISON: GRAIN BOUNDARY $\Leftrightarrow$ DISCLINATION





### COMPARISON: GRAIN BOUNDARY $\Leftrightarrow$ DISCLINATION





# **REDUCTION OF DISLOCATION DENSITY**



Dislocation densities in current state of the art layers?

How far can the concept be extended by simple growth of thick layers?

Controlled Epitaxial Lateral Overgrowth (ELO)

# EXPLORATORY EXPERIMENTS WITH ELO ON HPHT SINGLE CRYSTALS





# PATTERNING OF THE NUCLEATION LAYER



Fig. 6. Pyramidal array (a, b) and line/space (c, d) of heteroepitaxial diamond grown on Ir(001) surface.

Y. Ando, J. Kuwabara, K. Suzuki, A. Sawabe, DRM 13 (2004) 1975.



### RAMAN SPECTRA OF HETEROEPITAXIAL DIAMOND LAYERS ON Ir



Diamond on Ir/SrTiO<sub>3</sub>(001)

Diamond on Ir/Al<sub>2</sub>O<sub>3</sub>



A. Samato, .... A. Sawabe, T. Suzuki, Diamond Relat. Mater. 17 (2008) 1039.



### RAMAN SPECTRA OF HETEROEPITAXIAL DIAMOND LAYERS

Raman spectra of epitaxial diamond layers on silicon



Schreck, Hörmann, Roll, Bauer, Stritzker: NDFCT 11 (2001) 189.

### Raman spectra of a 475 µm thick diamond layer grown on Ir/YSZ/Si(001)





# SUMMARY

Mosaic spread of heteroepitaxial diamond on Ir/YSZ/Si(001) outperform former layers on Ir/SrTiO<sub>3</sub>(001) Mosaic spread (Lowest values ~0.1-0.3°) is in the range of standard IIa layers but still 2 orders of magnitude higher than for high quality IIa's Raman line width: lowest values ~ 2.5 cm<sup>-1</sup> Upscaling on Ir/YSZ/Si(001): 4 inch size for the Ir films and more than 10 cm<sup>2</sup> for the diamond (critical: homogeneity) First measurements of transient currents (TC) to test detector performance -> see contribution Elèni Berdermann Concepts for further reduction of dislocation densities: ELO



